

FDD3670

100V N-Channel PowerTrench MOSFET

General Description

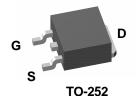
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

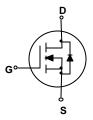
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{\text{DS(ON)}}$ specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- 34 A, 100 V. $R_{DS(ON)} = 32$ m Ω @ $V_{GS} = 10$ V $R_{DS(ON)} = 35$ m Ω @ $V_{GS} = 6$ V
- Low gate charge (57 nC typical)
- · Fast switching speed
- High performance trench technology for extremely low R_{DS(ON)}
- High power and current handling capability





Absolute Maximum Ratings T_A=25°C unless otherwise noted

	<u> </u>		
Symbol	Parameter	Ratings	Units
V _{DSS}	Drain-Source Voltage	100	V
V _{GSS}	Gate-Source Voltage	±20	V
I _D	Drain Current - Continuous (Note 1)	34	А
	Drain Current - Pulsed	100	
P _D	Maximum Power Dissipation @ T _C = 25°C (Note 1)	83	W
	@ T _A = 25°C (Note 1a)	3.8	
	@ $T_A = 25^{\circ}C$ (Note 1b)	1.6	
T _J , T _{STG}	Operating and Storage Junction Temperature Range	-55 to +175	°C

Thermal Characteristics

R ₀ JC	Thermal Resistance, Junction-to-Case	(Note 1)	1.8	°C/W
R _{0JA}	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

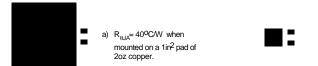
Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDD3670	FDD3670	13"	16mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Note	2)	I	I	I	I
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 50 \text{ V}, \qquad I_D = 7.3 \text{ A}$			360	mJ
l _{AR}	Maximum Drain-Source Avalanche Current				7.3	Α
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		92		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			10	μΑ
GSSF	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)		•	•	•	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	2.5	4	V
ΔV _{GS(th)} ΔT _J	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-7.2		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$\begin{split} &V_{GS} = 10 \text{ V}, &I_D = 7.3 \text{ A} \\ &V_{GS} = 10 \text{ V}, &I_D = 7.3 \text{ A}, &T_J = 125 ^{\circ}\text{C} \\ &V_{GS} = 6 \text{ V}, &I_D = 7.0 \text{ A} \end{split}$		22 39 24	32 56 35	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	25			Α
g FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_D = 7.3 \text{ A}$	15	31		S
Dvnamic	Characteristics					
Ciss	Input Capacitance	$V_{DS} = 50 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		2490		pF
Coss	Output Capacitance	f = 1.0 MHz		265		pF
Crss	Reverse Transfer Capacitance			80		pF
Switchin	g Characteristics (Note 2)		·			
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 50 \text{ V}, \qquad I_D = 1 \text{ A},$		16	26	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		10	18	ns
t _{d(off)}	Turn-Off Delay Time			56	84	ns
t _f	Turn-Off Fall Time			25	40	ns
Qg	Total Gate Charge	$V_{DS} = 50 \text{ V}, \qquad I_{D} = 7.3 \text{ A},$		57	80	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 10 \text{ V}$		11		nC
Q _{gd}	Gate-Drain Charge			15		nC
Drain-So	ource Diode Characteristics	and Maximum Ratings				
ls	Maximum Continuous Drain-Source	_			2.7	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.7 \text{ A}$ (Note 2)		0.72	1.2	V

Notes

b) $R_{\theta JA} = 96^{\circ}\text{C/W}$ on a minimum mounting pad.



Scale 1:1 on letter size paper

Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

R_{0,N} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0,C} is guaranteed by design while R_{0,CA} is determined by the user's board design.

Typical Characteristics

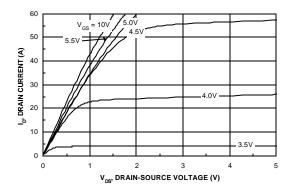


Figure 1. On-Region Characteristics.

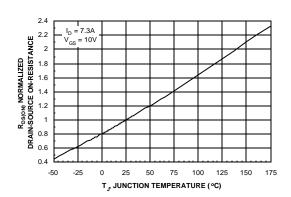


Figure 3. On-Resistance Variation with Temperature.

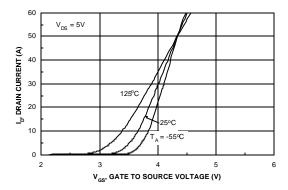


Figure 5. Transfer Characteristics.

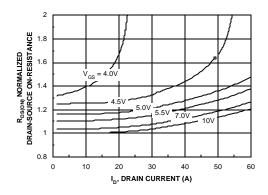


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

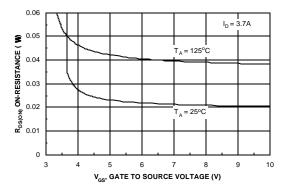


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

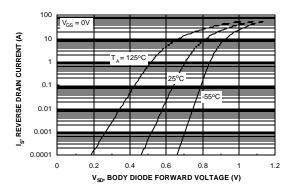
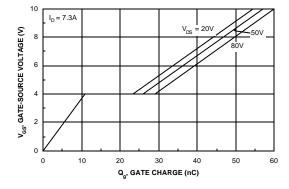


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



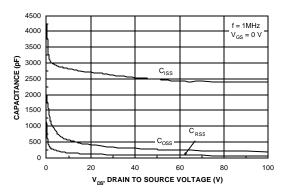
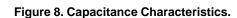
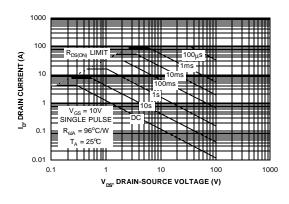


Figure 7. Gate Charge Characteristics.





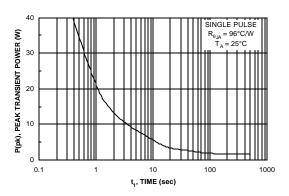


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

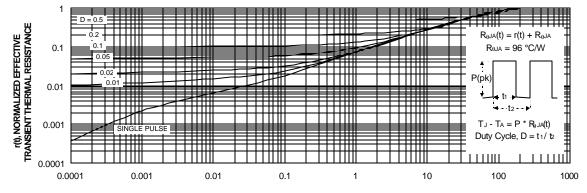


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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Rev. H3